

Supplementary Materials

Electron-Beam-Induced Fluorination Cycle for Long-Term Preservation of Graphene under Ambient Conditions

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Electronic supplementary information

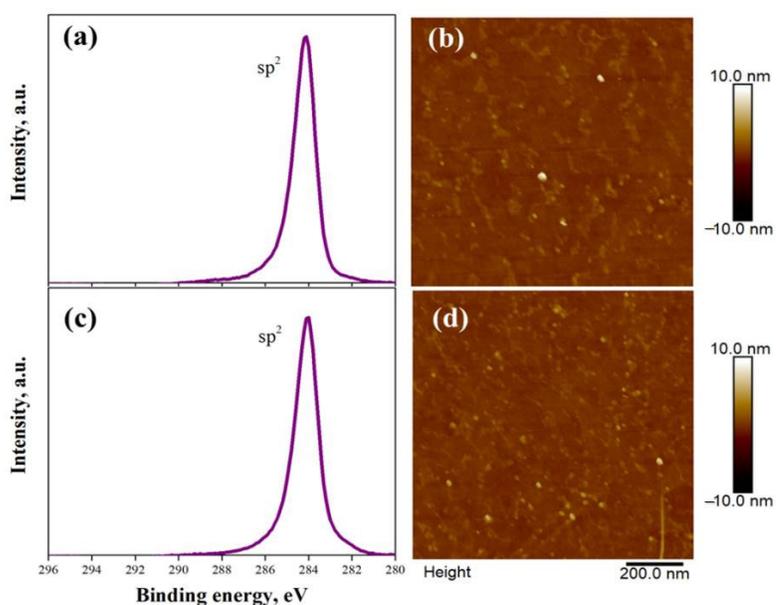


Figure S1. (a) and (c) are C1s XPS spectra of defluorinated graphene experienced the same fluorination/defluorination cycle and (b) and (d) are corresponding AFM images, respectively.

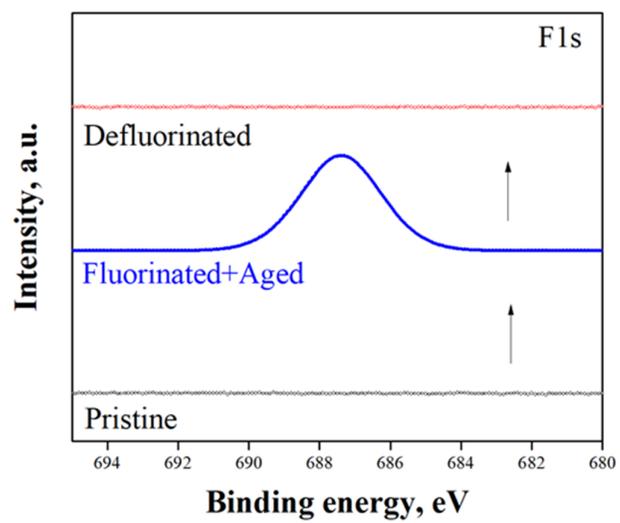


Figure S2. F1s XPS spectra of graphene sample at different fluorination/defluorination stage.